Effect of Band-offset Ratio on Characteristics of 405-nm InGaN Quantum-well Lasers 導電帶與價電帶井深比例對 405-nm 氮化銦鎵量子井雷射特性之影響

Liou, Bo-Ting; Kuo, Yen-Kuang; Yen, Sheng-Horng; Lin, Cheng-Yang

## Abstract

The effect of band-offset ratio on the characteristics of the 405-nm InGaN quantum-well lasers is studied numerically. Specifically, the optical properties are investigated when the band-offset ratio of the InxGa1-xN/InyGa1-yN heterojunction is 7/3. Compared to a band-off-set ratio of 3/7, which was widely accepted before the year 2002, the laser performance is better and the distribution of carrier concentration in the quantum wells becomes more uniform when the band-offset ratio is 7/3, which is accepted by most researchers recently. Several formulae are derived from simulations, which can be used as a handy tool to calculate the thickness of InxGa1-xN well layer in the 405-nm laser structure for specific indium compositions of InxGa1-xN well alyer and InyGa1-yN barrier layer.

Key words : InGaN; Band-Offset ratio; Quantum-well laser; Threshold current

## 中文摘要

本文以數值計算來探討導電帶與價電帶井深比例對 405-nm 氮化銦嫁量 子井雷射特性的影響。特別是導電帶與價電帶井深比例為 7/3 的 Inx, Ga1-xN/InyGa1-yN 異質結構的光學特性。比較顯示現今大家所認同的井 深比例為 7/3 比 2002 年以前一般所認同的井深比例為 3/7 有較佳的雷射 效能及在量子井有較均勻的載子濃度分布。本文亦由模擬的結果推導出 405nm 雷射結構在一些特定銦含量的披覆層時,其量子井厚度與量子井 銦含量的關係式,以作為設計的參考。

關鍵字:氮化銦鎵;導電帶與價電帶井深比例;量子井雷射;臨界電流